

N-channel 60 V, 0.0031 Ω typ., 70 A STripFET™ F7 Power MOSFET in a TO-220FP package

Datasheet - production data

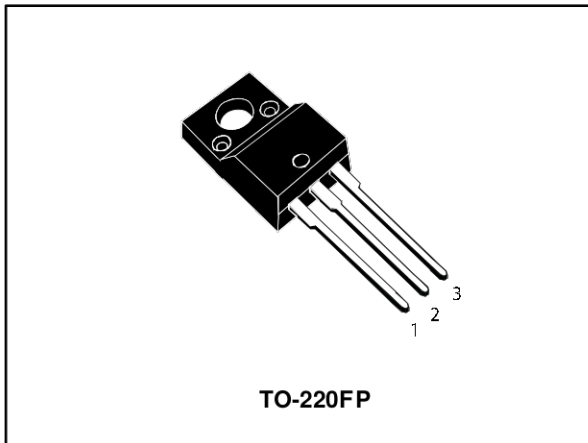
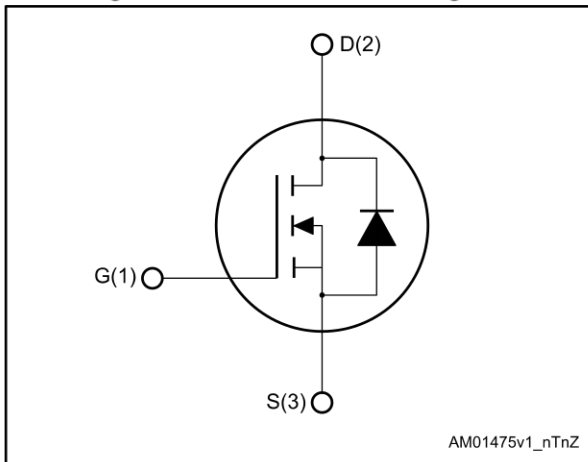


Figure 1: Internal schematic diagram



Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D | P _{TOT} |
|------------|-----------------|--------------------------|----------------|------------------|
| STF140N6F7 | 60 V | 0.0035 Ω | 70 A | 33 W |

- Among the lowest R_{DS(on)} on the market
- Excellent figure of merit (FoM)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

- Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

| Order code | Marking | Package | Packing |
|------------|---------|----------|---------|
| STF140N6F7 | 140N6F7 | TO-220FP | Tube |

Contents

| | | |
|----------|---|-----------|
| 1 | Electrical ratings | 3 |
| 2 | Electrical characteristics | 4 |
| | 2.1 Electrical characteristics (curves) | 6 |
| 3 | Test circuits | 8 |
| 4 | Package information | 9 |
| | 4.1 TO-220FP package information | 10 |
| 5 | Revision history | 12 |

1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|--------------------------------|---|------------|------|
| V _{DS} | Drain-source voltage | 60 | V |
| V _{GS} | Gate-source voltage | ±20 | V |
| I _D ⁽¹⁾ | Drain current (continuous) at T _{case} = 25 °C | 70 | A |
| | Drain current (continuous) at T _{case} = 100 °C | 50 | |
| I _{DM} ⁽²⁾ | Drain current (pulsed) | 280 | A |
| P _{TOT} | Total dissipation at T _{case} = 25 °C | 33 | W |
| E _{AS} ⁽³⁾ | Single pulse avalanche energy | 250 | mJ |
| dV/dt ⁽⁴⁾ | Drain-body diode dynamic dV/dt ruggedness | 7.1 | V/ns |
| V _{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T _c = 25 °C) | 2500 | V |
| T _{stg} | Storage temperature | -55 to 175 | °C |
| T _j | Maximum junction temperature | 175 | |

Notes:

- (1) Current is limited by package.
- (2) Pulse width is limited by safe operating area.
- (3) Starting T_j = 25°C, I_D = 20 A, V_{DD} = 30 V.
- (4) I_{SD} = 70 A; di/dt = 600 A/μs; V_{DD} = 48 V; T_j < T_{jmax}

Table 3: Thermal data

| Symbol | Parameter | Value | Unit |
|-----------------------|-------------------------------------|-------|------|
| R _{thj-case} | Thermal resistance junction-case | 4.5 | °C/W |
| R _{thj-amb} | Thermal resistance junction-ambient | 62.5 | |

2 Electrical characteristics

($T_{\text{case}} = 25\text{ °C}$ unless otherwise specified)

Table 4: Static

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|-----------------------------------|---|------|--------|--------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$ | 60 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$ | | | 1 | μA |
| | | $V_{GS} = 0\text{ V}$, $V_{DS} = 60\text{ V}$, $T_j = 125\text{ °C}$ | | | 100 | |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0\text{ V}$, $V_{GS} = 20\text{ V}$ | | | 100 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 2 | | 4 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$, $I_D = 35\text{ A}$ | | 0.0031 | 0.0035 | Ω |

Table 5: Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------|------------------------------|--|------|------|------|-------------|
| C_{iss} | Input capacitance | $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$ | - | 3100 | - | pF |
| C_{oss} | Output capacitance | | - | 1520 | - | |
| C_{rss} | Reverse transfer capacitance | | - | 193 | - | |
| Q_g | Total gate charge | $V_{DD} = 30\text{ V}$, $I_D = 70\text{ A}$, $V_{GS} = 10\text{ V}$ (see Figure 14: "Test circuit for gate charge behavior") | - | 55 | - | nC |
| Q_{gs} | Gate-source charge | | - | 19 | - | |
| Q_{gd} | Gate-drain charge | | - | 18 | - | |

Table 6: Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 30\text{ V}$, $I_D = 35\text{ A}$ $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ (see Figure 13: "Test circuit for resistive load switching times" and Figure 18: "Switching time waveform") | - | 24 | - | ns |
| t_r | Rise time | | - | 68 | - | |
| $t_{d(off)}$ | Turn-off delay time | | - | 39 | - | |
| t_f | Fall time | | - | 20 | - | |

Table 7: Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------|--------------------------|---|------|------|------|------|
| $V_{SD}^{(1)}$ | Forward on voltage | $V_{GS} = 0 \text{ V}$, $I_{SD} = 70 \text{ A}$ | - | | 1.2 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 70 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 48 \text{ V}$ (see Figure 15: "Test circuit for inductive load switching and diode recovery times") | - | 42.4 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 38.2 | | nC |
| I_{RRM} | Reverse recovery current | | - | 1.8 | | A |

Notes:

⁽¹⁾ Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

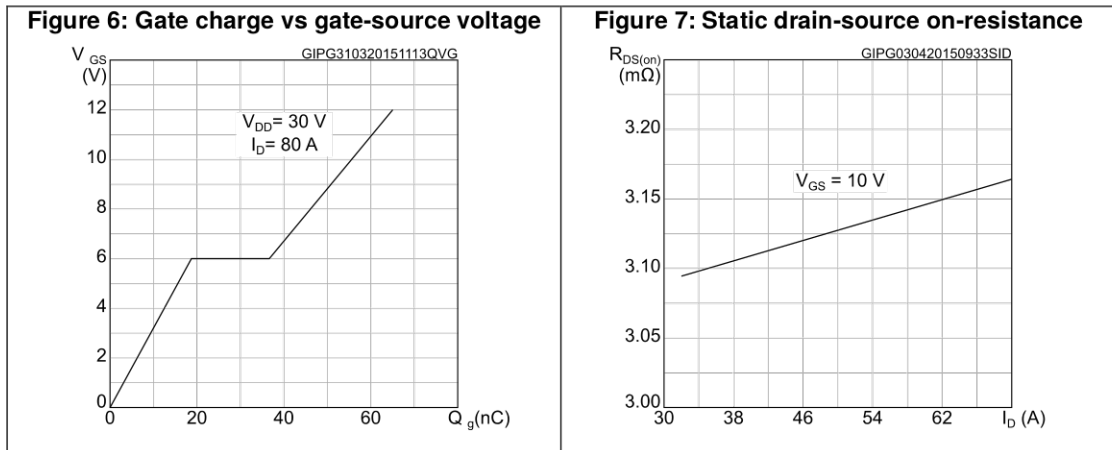
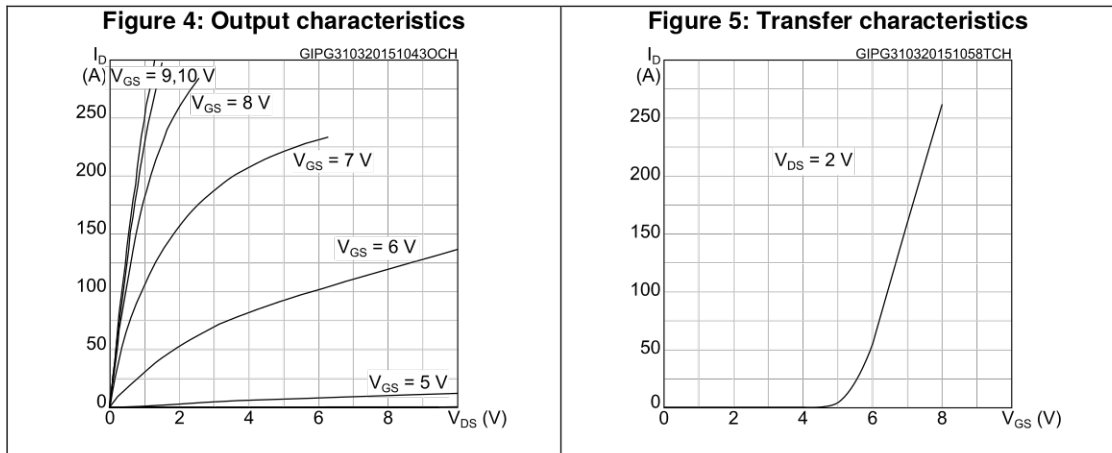
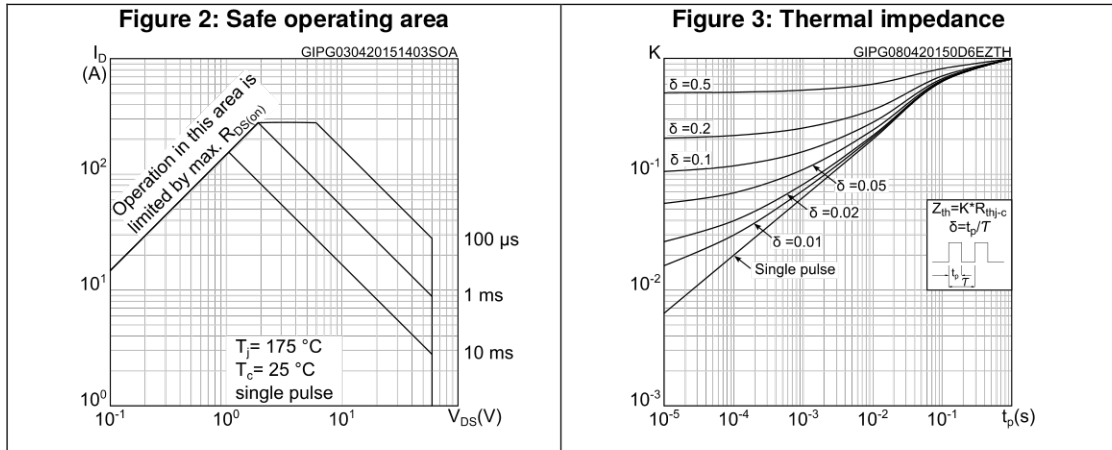


Figure 8: Capacitance variations

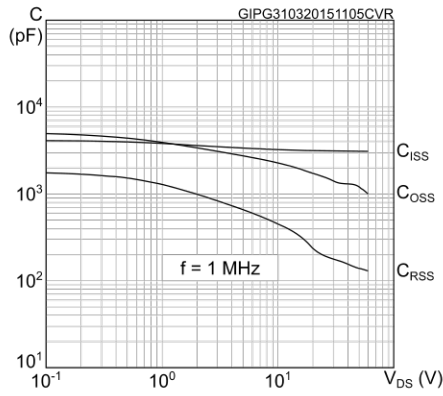


Figure 9: Normalized gate threshold voltage vs temperature

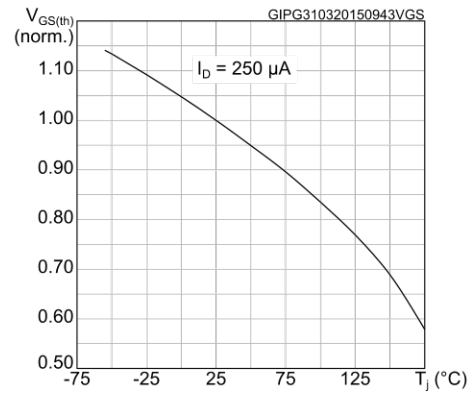


Figure 10: Normalized on-resistance vs temperature

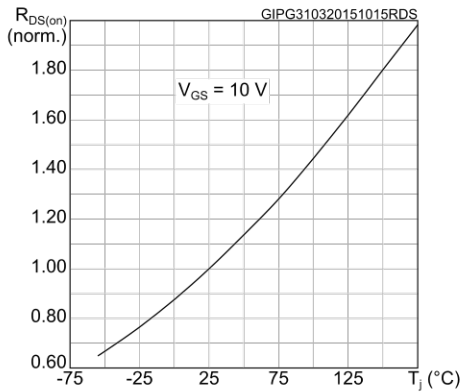


Figure 11: Normalized V(BR)DSS vs temperature

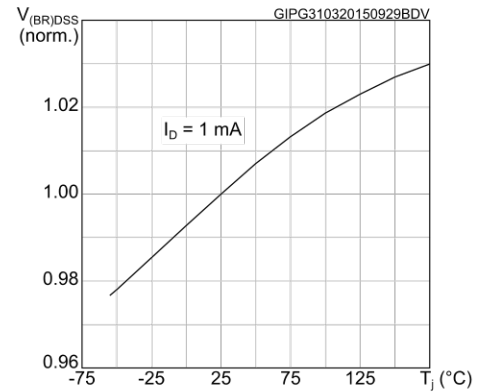
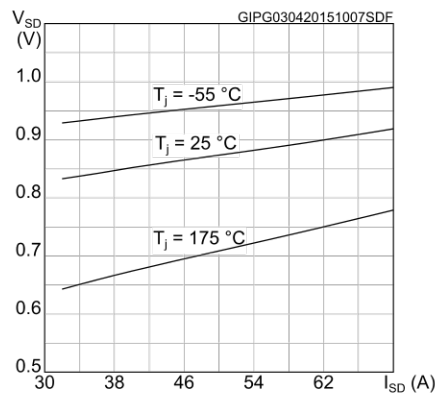
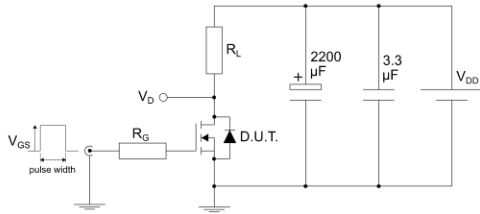


Figure 12: Source-drain diode forward characteristics



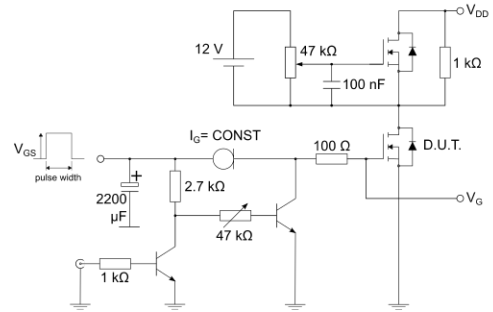
3 Test circuits

Figure 13: Test circuit for resistive load switching times



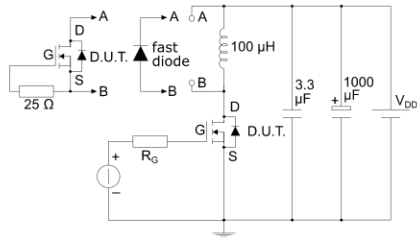
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Figure 14: Test circuit for gate charge behavior



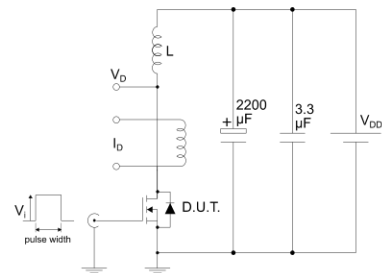
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Figure 15: Test circuit for inductive load switching and diode recovery times



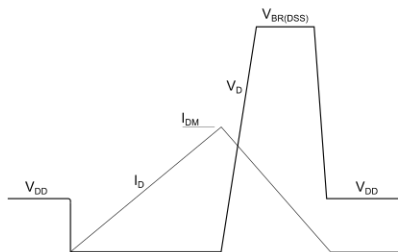
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Figure 16: Unclamped inductive load test circuit



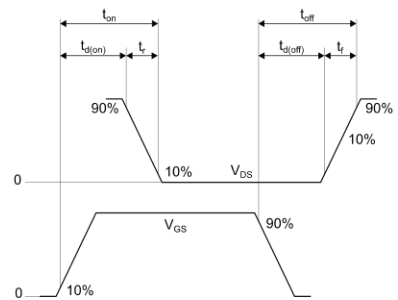
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Figure 17: Unclamped inductive waveform



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Figure 18: Switching time waveform



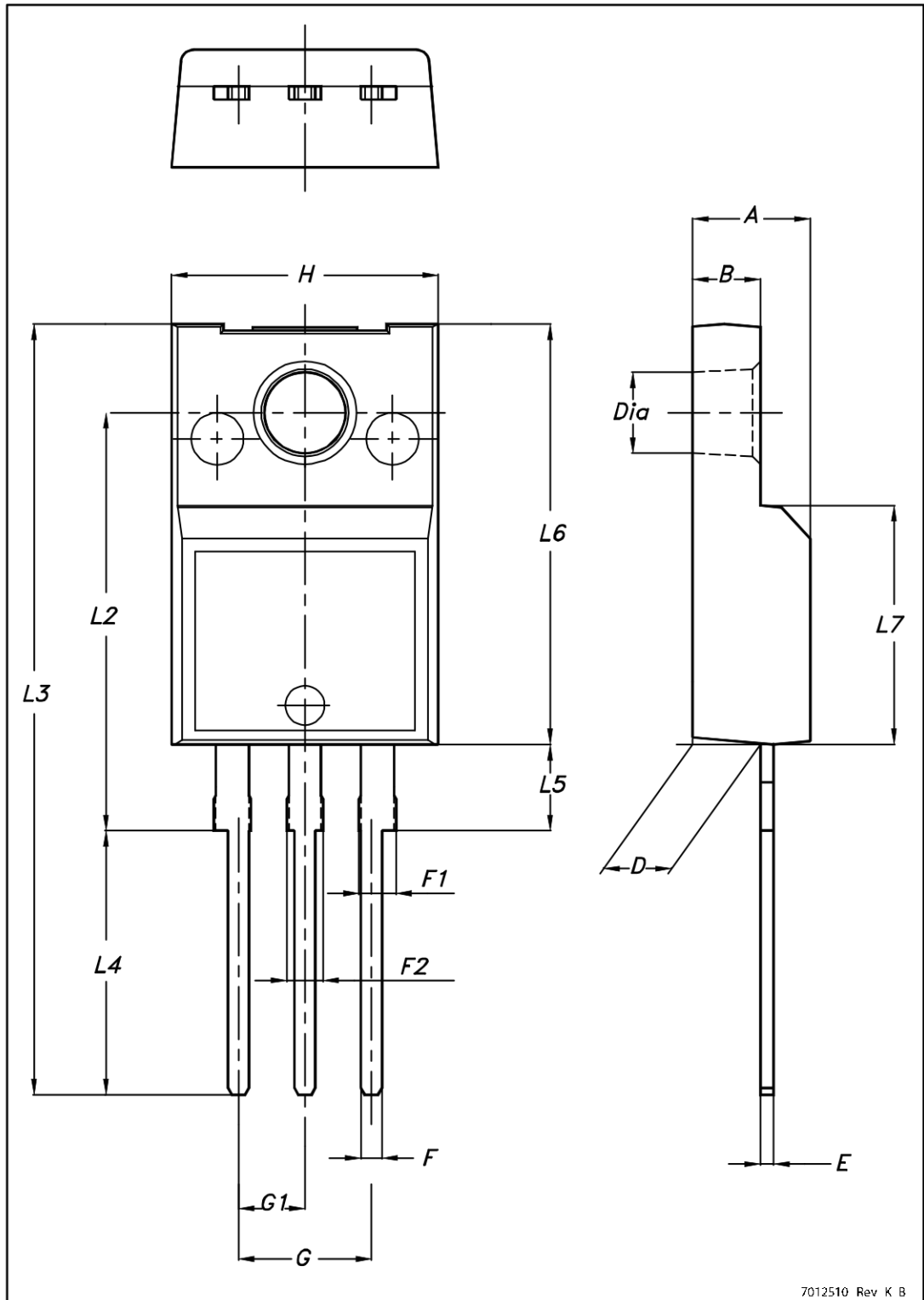
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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220FP package information

Figure 19: TO-220FP package outline



7012510 Rev K B

Table 8: TO-220FP package mechanical data

| Dim. | mm | | |
|------|------|------|------|
| | Min. | Typ. | Max. |
| A | 4.4 | | 4.6 |
| B | 2.5 | | 2.7 |
| D | 2.5 | | 2.75 |
| E | 0.45 | | 0.7 |
| F | 0.75 | | 1 |
| F1 | 1.15 | | 1.70 |
| F2 | 1.15 | | 1.70 |
| G | 4.95 | | 5.2 |
| G1 | 2.4 | | 2.7 |
| H | 10 | | 10.4 |
| L2 | | 16 | |
| L3 | 28.6 | | 30.6 |
| L4 | 9.8 | | 10.6 |
| L5 | 2.9 | | 3.6 |
| L6 | 15.9 | | 16.4 |
| L7 | 9 | | 9.3 |
| Dia | 3 | | 3.2 |

5 Revision history

Table 9: Document revision history

| Date | Revision | Changes |
|-------------|----------|---|
| 09-Apr-2015 | 1 | First release. |
| 17-Apr-2015 | 2 | Throughout document: - minor text edits - updated drain-source on-resistance values |
| 14-Jan-2016 | 3 | Updated Table 2: "Absolute maximum ratings" . |

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